



Form PTO-1449 (modified)	ATTY. DOCKET NO. MICS:0098 (02-1041)	SERIAL NO. 10/609,089
List of Patents and Publications For Applicant's Information Disclosure Statement	APPLICANT Bill Baggenstoss	
(Use several sheets if necessary)	FILING DATE June 27, 2003	GROUP 2818

U.S. PATENT DOCUMENTS

EXAM. INIT.	REF. DES.	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
DM	A1	6,418,008	07/09/02	Jost et al.	361	303	03/06/01

FOREIGN PATENT DOCUMENTS

EXAM. INIT.	REF. DES.	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	TRANSLATION

OTHER ART

(Author, Title, Journal, Volume, Pertinent Pages, & Date)		
PM	C1	Murguia, James E., et al., Merging Focused Ion Beam Patterning and Optical Lithography in Device and Circuit Fabrication, Journal of Vacuum Science Technology B, Issue 8 (6), Nov/Dec 1990, pages 1374-1379
PM	C2	Preuninger, J., et al., High Order Lens Aberration Monitor, Microelectronic Engineering 53 (2000), pages 129-132
EXAMINER	DATE CONSIDERED	
	7/5/05	

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Information Disclosure Statement--PTO-1449 (Modified)



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(Use several sheets if necessary)	FILING DATE June 27, 2003	GROUP Unassigned

U.S. PATENT DOCUMENTS

EXAM. INIT.	REF. DES.	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
DM	A1	6,569,574	05/27/03	Bill Baggenstoss	430	5	10/18/99
DM	A2	6,440,612	08/27/02	Bill Baggenstoss	430	5	09/01/99
DM	A3	6,401,236	06/04/02	Bill Baggenstoss et al.	716	19	04/05/99
DM	A4	6,374,396	04/16/02	Bill Baggenstoss et al.	716	19	12/04/98
DM	A5	6,319,644	11/20/01	Pierrat et al.	430	30	02/12/01
DM	A6	6,284,419	09/04/01	Pierrat et al.	430	30	01/24/01
DM	A7	6,120,952	09/19/00	Pierrat et al.	430	30	10/01/98

FOREIGN PATENT DOCUMENTS

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OTHER ART

(Author, Title, Journal, Volume, Pertinent Pages, & Date)	
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<i>[Signature]</i>	7/6/05

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